


<b>Search Notes</b> 	<b>Application/Control No.</b> 10580496	<b>Applicant(s)/Patent Under Reexamination</b> RAIJMAKERS ET AL.
	<b>Examiner</b> SHEELA C CHAWAN	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	115, 128,	3/16/09	SCC
705	2, 3,	"	"
455	556.1,	"	"
2	114	"	"
607	107, 104, 108,	"	"
345	419	"	"
378	196,	"	"
600	27,26,28	"	"
160	10	"	"
382	115, 128	3/28/10	SCC
345	418	3/28/10	SCC
705	2	3/28/10	SCC
SEARCH UP-DATE		3/28/10	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	3/16/09	SCC
INVENTOR SEARCH.	"	"
SEARCH UP-DATE	11/2/09	SCC
SEARCH EAST AND OTHER DATA BASE, SEE THE SEARCH HISTORY.	3/28/10	SCC
382/115,128.ccls.	3/28/10	SCC
345/418,419.ccls.	3/28/10	SCC
705/2,3.ccls.	3/28/10	SCC
INTERFERENCE SEARCH	3/28/10	SCC
SEARCH IEEE OR INSPECT DATABASE.	3/28/10	SCC
SEARCH UP-DATE	3/28/10	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	115, 128	3/28/10	SCC

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**INTERFERENCE SEARCH**

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
345	418	3/28/10	SCC
705	2	3/28/10	SCC

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